


<b>Search Notes</b>  	<b>Application/Control No.</b>  10659744	<b>Applicant(s)/Patent Under Reexamination</b>  NABEYAMA ET AL.
	<b>Examiner</b>  Tran, Dzung D	<b>Art Unit</b>  2613

SEARCHED			
Class	Subclass	Date	Examiner
398	81, 147	12/09/2007	TD

SEARCH NOTES		
Search Notes	Date	Examiner
398/class as listed (USPAT; US-PGPUB; EPO; JPO and text search). See search history printout	12/09/2007	TD

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner